Deep Learning Cognitive Computing Techniques and Their Application in Cybersecurity and Forensics

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Message from the Guest Editors

This Special Issue invites a broad range of topics across emerging deep learning cognitive computing techniques applications in cybersecurity and forensics, some specific topics include, but are not limited to:

- Application of deep learning cognitive computing techniques in cybersecurity or forensics;
- Deep learning for cyber forensics;
- Deep learning enabled cybersecurity or forensics engine;
- Novel machine learning approaches to cybersecurity or forensics;
- Deep learning methods for cybersecurity or forensics;
- Deep learning methods for database security or forensics.

Special Issue

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Message from the Editor-in-Chief

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